#2

Form PTO-1449		ATTY. DOCKET NO.	SERIAL NO.	
	LIST OF PATENTS AND PUBLICATIONS FOR	JG00069	09/766046	P.T.
	APPLICANT'S INFORMATION DISCLOSURE	Ramdani et al.		u.s 1660
	STATEMENT	FILING DATE	GROUP	2.2
	(Use Several Sheets if Necessary)	01/19/01	2811	60

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER								ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE
27/Th	AA	5	2	7	0	2	9	8	12/14-93	Ramesh	505	1	8/4/92
	AB	5	4	1	8	3	8	9	5/23/95	Watanabe	257	295	11/9/93
	AC	5	2	4	8	5	6	4	9/28/93	Ramesh	428	688	12/9/92
	AD	5	1	5	5	6	5	8	10/13/92	Inam et al.	361	321	3/5/92
	ΑE	6	0	5	5	1	7	9	4/25/00	Koganei et al.	365	158	5/17/99
	AF	5	3	2	6	7	2	1	7/5/94	Summerfelt	437	131	5/1/92
	AG	5	3	1	0	7	0	7	5/10/94	Oishi et al.	501	126	9/28/92
	AH	4	9.	9.	9_	_8_	4.	2	3/12/91	-Huang-et-al:	372	45	3/1/89
1	ΑI	5	8	7	4	8	6	0	2/23/99	Brunel et al.	330	285	12/4/96
	AJ	6	0	0	2	3	7	5	12/14/99	Corman et al.	343	853	9/2/97
	AK	4	8	8	2	3	0	0	11/21/89	Inoue et al.	437	236	10/6/88
I	AL	5	6	7	4	3	6	6	10/7/97	Hayashi et al.	204	298.09	6/7/95
	AM	5	7	3	1	2	2	0	3/24/98	Tsu et al.	437	60	6/7/95
J	AN	5	8	2	8	0	8	0	10/27/98	Yano et al.	257	43	8/17/95
2%h	AO	5	8	0	1	1	0	5	9/1/98	Yano et al.	438	785	6/14/96

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

27K	AP	"Optimizing GMR Spin Valves: The Outlook for Improved Properties", W. F. Englhoff et al., 1998 Int'l NonVolatile Memory Technology Conference, pp. 34-37.
	AQ	"Processing and Performance of Piezoelectric Films", Y. Wang et al., Univ. of MD, Wilcoxon Research Co., and Motorola Labs.
	AP	"Nonlinear acoustoelectric interactions in GaAs/LiNbO ₃ structures", M. Rotter et al., 1999 American Institute of Physics, pp. 965-967.
	AS	"Surface acoustic wave propagation on lead zirconate titanate thin films", K. Sreenivas et al., App. Phys. Lett. 52(9), 29 February 1988, pp. 709-711.
	AT	"Single Chip fused hybrids for acousto-electric and acousto-optic applications", M. Rotter et al., 1997 American Institute of Physics, pp. 2097-2099.
	AU	"Surface Acoustic Wave Propagation in PZT/YBCO/SrTiO ₃ and PbTi O ₃ /YBCO/SrTiO ₃ Epitaxial Heterostructures", Dept. of Physics & Astrophysics, Univ. of Delhi, pp. 275-283.
3KK	AV	"Ferroelectric Field Effect Transisitor Based on Epitaxial Perovskite Heterostructures", S. Mathews et al., American Association for the Advancement of Science, 1997, pp.238-240.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL			OCU JME		NT				ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE
	AW	6	1	0	3	0	0	8	8/15/00	McKee et al.	117	2	7/30/98
	AX	5	2	2	5	0	3	1	7/6/93	McKee et al.	156	612	4/10/91
	AY												

FOREIGN PATENT DOCUMENTS

-	EXAMINER INITIAL	DOCU -NUME		NT						GRANT -DATE-	COUNTRY	CLASS	SUB CLASS	TRANS YES	LATION_ NO
Ì		AZ	9	9	1	4	8	0	4	3/25/99	PCT	H01L	21/258	X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

ВА	"Formation of Si Epi./Mg0-Al ₂ 0 ₃ Epi./Si0 ₃ /Si and Its Epitaxial Film Quality," Masao Mikami et al., Fundamental Research Laboratories and Microelectronics Laboratories, pp. 31-34.
BB	"An Epitaxial Si/Insulator/Si Structure Prepared by Vacuum Deposition of CaF ₂ and Silicon," T. Asano et al., Graduate School of Science and Engineering, Tokyo Institute of Technology, pp. 143-151.
BE	"Reaction and Regrowth Control of Ce0 ₂ on Si(111) Surface for the Silicon-On-Insulator Structure," T. Chikyow et al., Appl. Phys. Lett. 65(8), 22 August 1994, pp. 1030-1032.
BD	"Epitaxial Growth of Ce0 ₂ (100) Films on Si(100) Substrates by Dual Ion Beams Reactive Sputtering," J.F. Kang et al., Solid State Communications, Vol. 108, No. 4, pp. 225-227.
BE	"Vertical-Cavity Surface-Emitting Lasers Come of Age," Robert A. Morgan et al., SPIE, Vol. 2683, pp. 18-29.
BF	"Technical Analysis of Qualcomm QCP-800 Portable Cellular Phone(Transmitter Circuitry)," Talus Corporation, Qualcomm QCP-800 Technical Analysis Report, December 10, 1996, pp. 5-8.
BG	"Properties of GaAs Si Grown by Molecular Beam Epitaxy,"R. Houdre et al., Solid State and Molecular Sciences, 1990, pp. 91-114.
ВН	"Gallium Arsenide and Other Compound Semiconductors on Silicon," S.F. Fang et al., J. Appl. Phys. 68(7), 1 October 1990, pp. R31-R58.

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